

IGBT³ Chip

FEATURES:

- 1200V Trench + Field Stop technology
- 120µm chip
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

This chip is used for:

- power module
- Applications:
- drives



Chip Type	V _{CE}	I Cn	Die Size	Package	Ordering Code
SIGC84T120R3L	1200V	75A	9.13 x 9.15 mm ²	sawn on foil	Q67050- A4266-A101

MECHANICAL PARAMETER:

Raster size	9.13 x 9.15	mm	
Emitter pad size (include gate pad)	7.61 x 7.67		
Gate pad size	1.14 x 1.14		
Area total / active	83.5 / 63.6	mm ²	
Thickness	120	μm	
Wafer size	150	mm	
Flat position	90	grd	
Max.possible chips per wafer	164 pcs		
Passivation frontside	Photoimide		
Emitter metallization	3200 nm AlSiCu		
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding		
Die bond	electrically conductive glue or solder		
Wire bond	Al, <500µm		
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm		
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C		



MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, Tj=25 °C	V _{CE}	1200	V
DC collector current, limited by T _{jmax}	I _C	1)	А
Pulsed collector current, t _p limited by T _{jmax}	I _{cpuls}	225	А
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T _j , T _{stg}	-55 +150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
	Symbol	Conditions	min.	typ.	max.	
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V , I _C = 3 mA	1200			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =75A	1.35	1.65	2.05	V
Gate-emitter threshold voltage	V _{GE(th)}	$I_C=3mA$, $V_{GE}=V_{CE}$	5.0	5.8	6.5	
Zero gate voltage collector current	I _{CES}	V_{CE} =1200V , V_{GE} =0V			10	μA
Gate-emitter leakage current	I _{GES}	V_{CE} =0V , V_{GE} =20V			600	nA
Integrated gate resistor	R _{Gint}			10		Ω

ELECTRICAL CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions	Value			Unit
Falameter	Symbol		min.	typ.	max.	
Input capacitance	Ciss	V _{CE} =25V,		5345		pF
Output capacitance	Coss	$V_{GE}=0V$,		280		
Reverse transfer capacitance	Crss	f=1MHz		242		

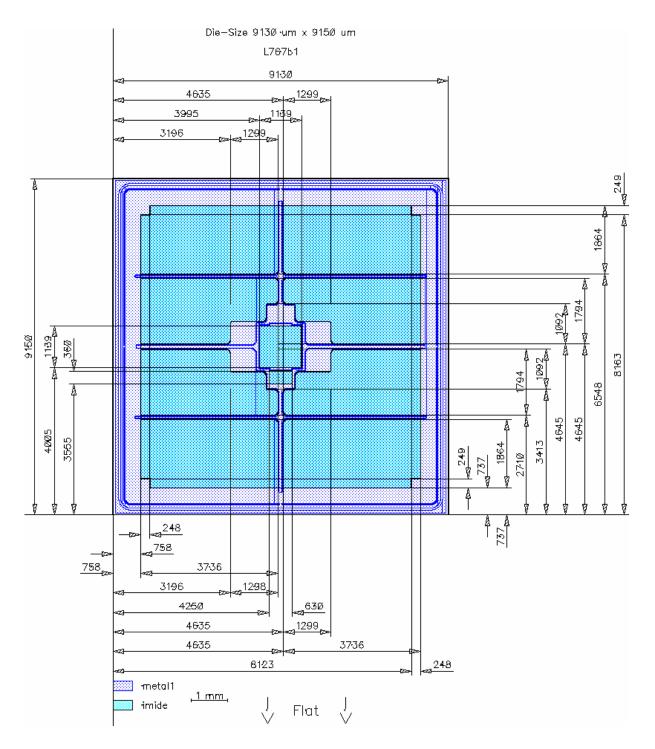
SWITCHING CHARACTERISTICS (tested at component), Inductive Load

Parameter	Symbol	Conditions ¹⁾	Value			Unit
			min.	typ.	max.	onn
Turn-on delay time	t _{d(on)}	$T_{\rm j}$ =125°C		0.29		μs
Rise time	tr	$V_{\rm CC} = 600 \text{V},$		0.05		
Turn-off delay time	$t_{d(off)}$	I _C =75A, V _{GE} =-15/15V,		0.52		
Fall time	t _f	R _G = 4.7Ω		0.09		

 $^{1)}$ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet	tbd	

DESCRIPTION:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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